IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of

Atty. Docket

FRIEDRICH HAPKE

DE 010056

Serial No.

Group Art Unit

Filed: CONCURRENTLY

Ex.

Title: ARRANGEMENT AND METHOD FOR TESTING INTEGRATED CIRCUITS

Commissioner for Patents Washington, D.C. 20231

PRELIMINARY AMENDMENT

Sir:

Prior to calculation of the filing fee and examination, please amend the above-identified application as follows:

IN THE CLAIMS

Please amend claim 5 as follows:

5. (amended) The arrangement as claimed in claim 3, wherein a test pattern counter (14; 28) is provided which counts a clock signal and supplies the counting result to the bit flipping controller (6; 27) and/or the masking logic circuit (13; 29).

REMARKS

The foregoing amendments to the claims were made solely to

'avoid' filing the claims in the multiple dependent form so as to avoid the additional filing fee.

The claims were not amended in order to address issues of patentability and Applicant respectfully reserves all rights he may have under the Doctrine of Equivalents. Applicant furthermore reserves his right to reintroduce subject matter deleted herein at a later time during the prosecution of this application or continuing applications.

Respectfully submitted,

Michael E. Marion, Reg. 32,266

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APPENDIX

Amended claim 5

5. (amended) The arrangement as claimed in claim 3—or 4, wherein a test pattern counter (14; 28) is provided which counts a clock signal and supplies the counting result to the bit flipping controller (6; 27) and/or the masking logic circuit (13; 29).